

ID	$R_{DS(ON)}(MAX)$	VDSS
25A	180mΩ	800V

Applications:

- LED Lighting
- Telecom
- UPS(Uninterruptible Power Supply)
- SMPS(Switch Mode Power Supply)

Features:

- Excellent ESD robustness
- Excellent high commutation ruggedness
- Low RDS(on) per chip area(Low FOM)
- Low gate charge

Ordering Information

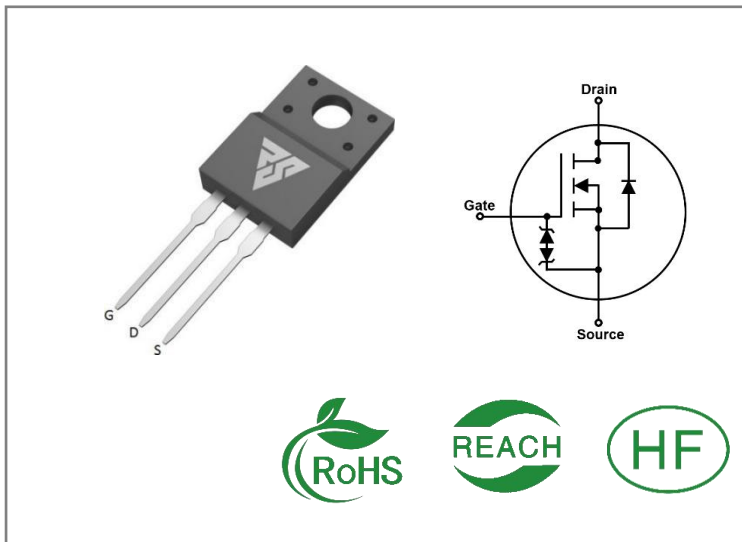
Part Number	Package	Marking	Packing	Qty.
RSE80R180F	T0-220F	RSE80R180F	Tube	50 PCS

Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RSE80R180F	Units
VDSS	Drain-to-Source Voltage	800	V
ID	Continuous Drain Current $T_C = 25^\circ\text{C}$	25	A
ID	Continuous Drain Current $T_C = 100^\circ\text{C}$	16	
IDM	Pulsed Drain Current (Note*1)	75	
PD	Power Dissipation	37	W
VGS	Gate- to- Source Voltage	± 20	V
EAS	Single Pulse Avalanche Energy $L = 30\text{mH}, V_{DD} = 100\text{V}, I_D = I_{AS}, T_j = 25^\circ\text{C}$	960	mJ
dv/dt	MOSFET dv/ dt ruggedness $V_{DS} = 0 \dots 400\text{V}$	50	V/ns
dv/dt	Reverse diode dv/dt $V_{DS} = 0 \dots 400\text{V}, T_j = 25^\circ\text{C}, I_{SD} \leq I_D$	15	V/ns
TL TPKG	Maximum Temperature for Soldering	300	$^\circ\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	260	
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

Symbol	Parameter	RSE80R180F	Units	Test Conditions
R θ JC	Junction-to-Case	3.4	$^{\circ}\text{C} / \text{W}$	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}\text{C}$
R θ JA	Junction-to- Ambient	80		1 cubic foot chamber, free air.

OFF Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	800	--	--	V	VGS=0V ID=0.25mA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	VDS=800V VGS=0V
IGSS	Gate- to- Source Forward Leakage	--	--	1	μA	VGS=20V VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-1		VGS=-20V VDS=0V

ON Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance(Note*2)	--	160	180	m Ω	VGS=10V ID=12A
VGS(TH)	Gate Threshold Voltage	3	4	5	V	VGS=VDS ID=0.25mA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	27	--	nS	VDS=400V ID=12A VGS=10V RG=4.7 Ω
trise	Rise Time	--	18	--		
td(OFF)	Turn- OFF Delay Time	--	89	--		
tfall	Fall Time	--	15	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	2850	--	pF	VGS=0V VDS=50V f=1.0MHz
Coss	Output Capacitance	--	90	--		
Crss	Reverse Transfer Capacitance	--	2.4	--		
Qg	Total Gate Charge	--	58	--	nC	VDS=400V ID=10A VGS=12V
Qgs	Gate- to- Source Charge	--	16	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	20	--		
RG	Gate resistance	--	4.5	--	Ω	f = 1MHz ID= 0A(open drain)

Source- Drain Diode Characteristics

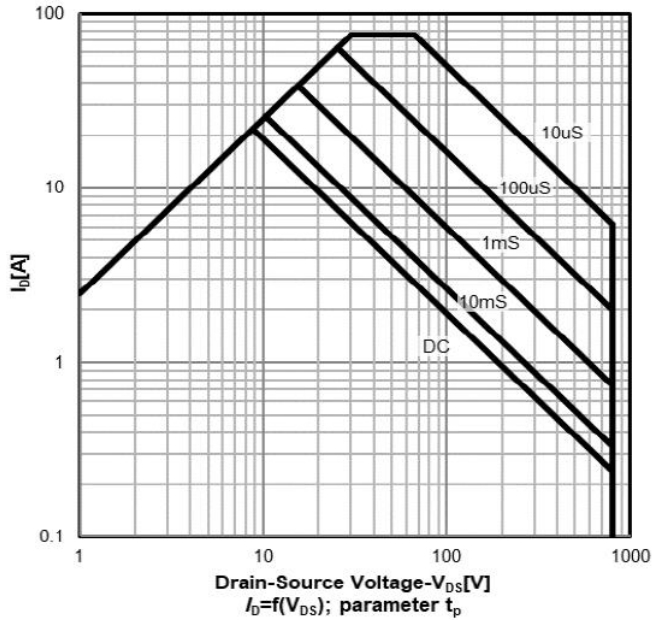
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	25	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	100	A	
VSD	Diode Forward Voltage	--	--	1.4	V	IS=20A VGS=0V
trr	Reverse Recovery Time	--	400	--	nS	VDD=400V IS=12A di/dt=100A/μs
Qrr	Reverse Recovery Charge	--	6.4	--	μC	
Irr	Reverse recovery current	--	30	--	A	

Notes:

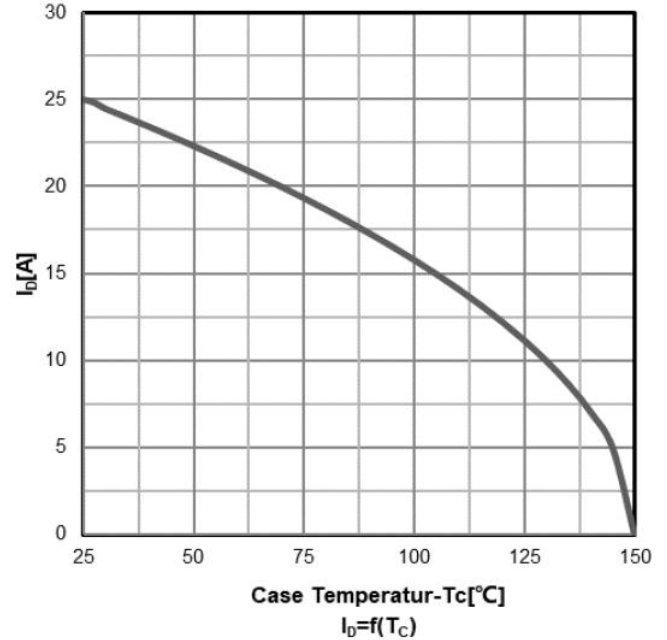
- * 1. Repetitive rating; pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%

Typical Feature Curve

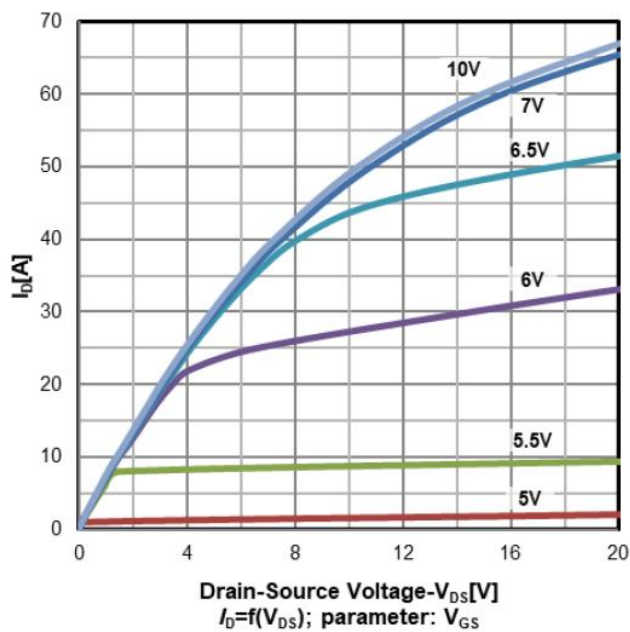
Safe operating area $T_C=25\text{ }^{\circ}\text{C}$
Non FullPAK



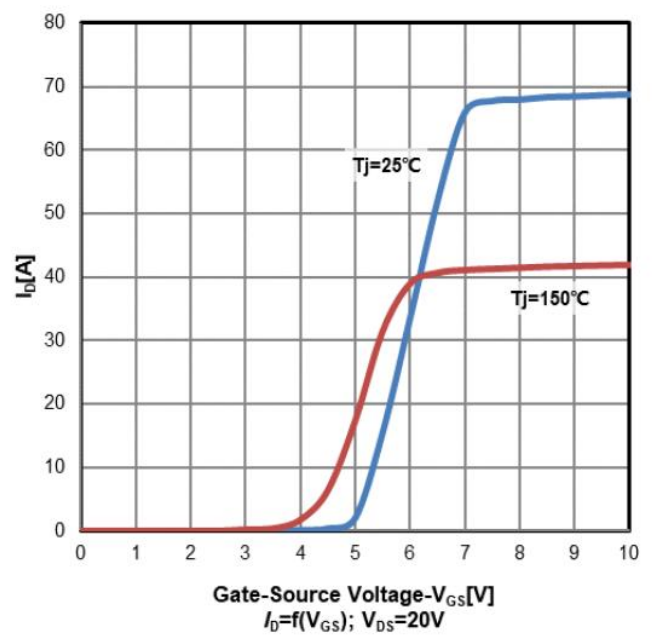
Drain current vs temperature



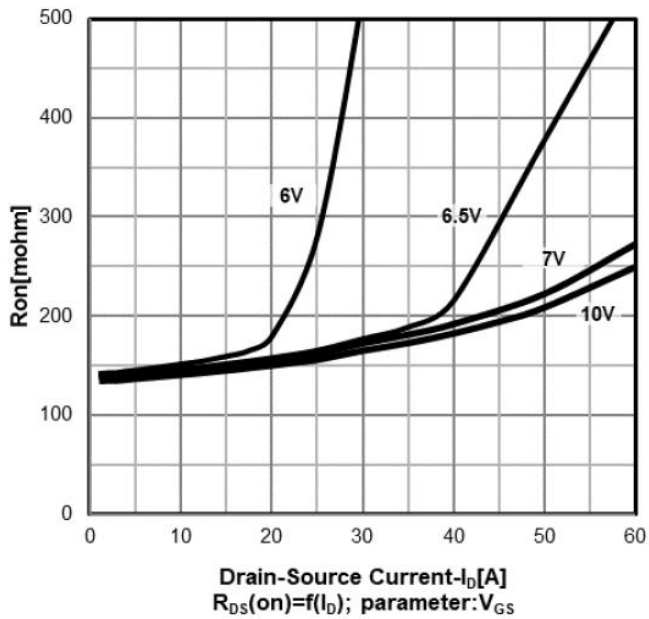
Typ. output characteristics $T_J=25\text{ }^{\circ}\text{C}$



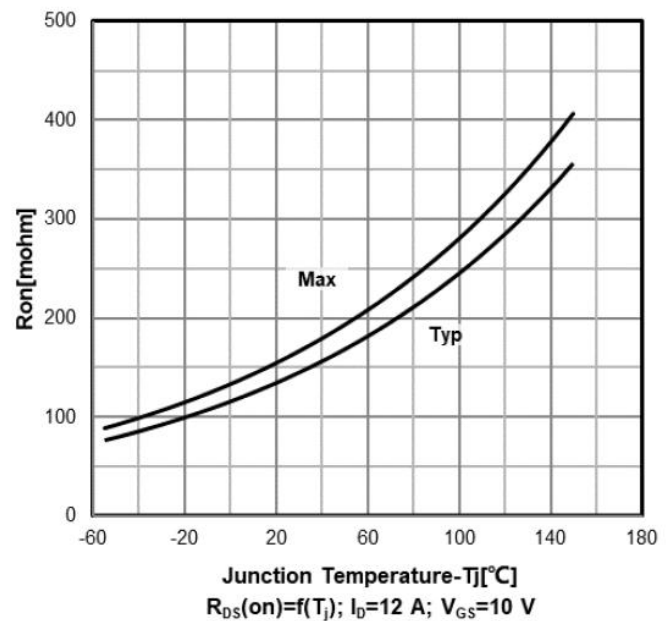
Typ. transfer characteristics



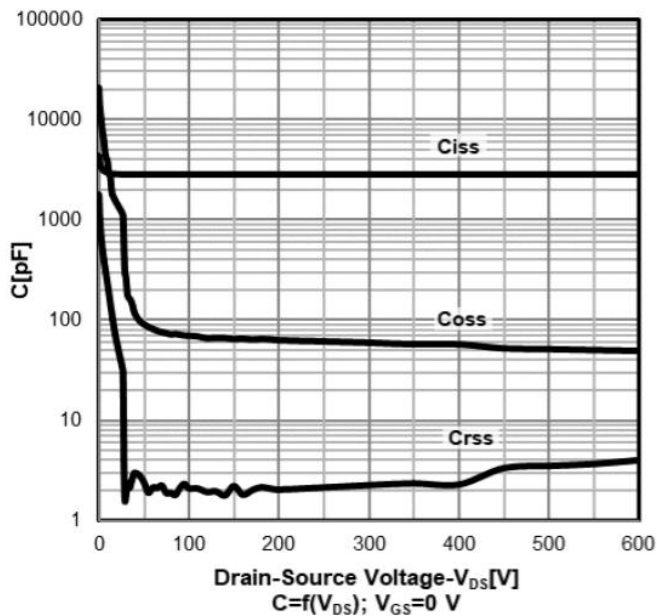
Typ. drain-source on-state resistance



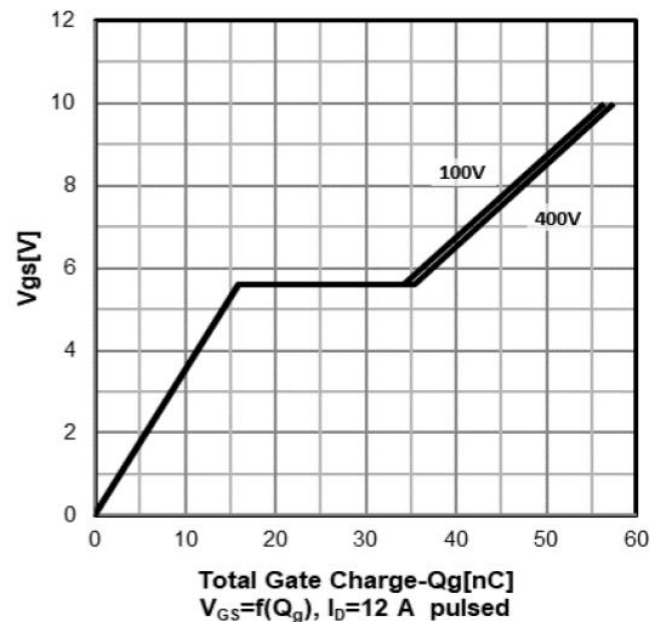
On resistance vs temperature



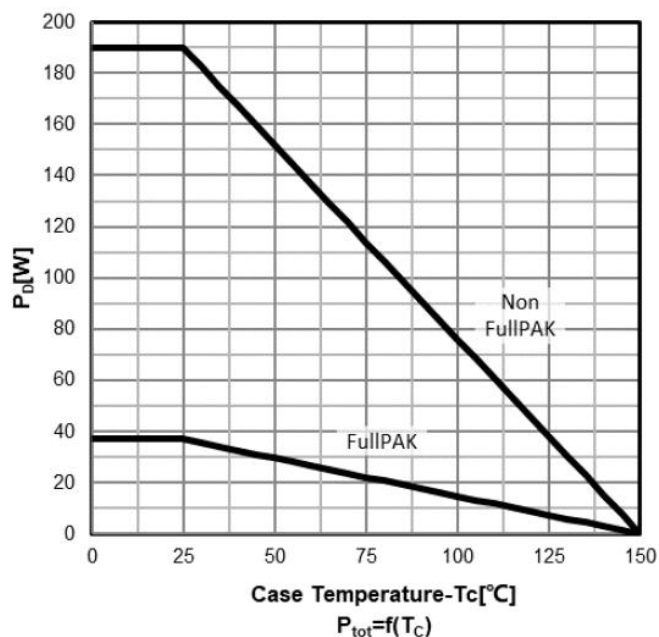
Typ. capacitances



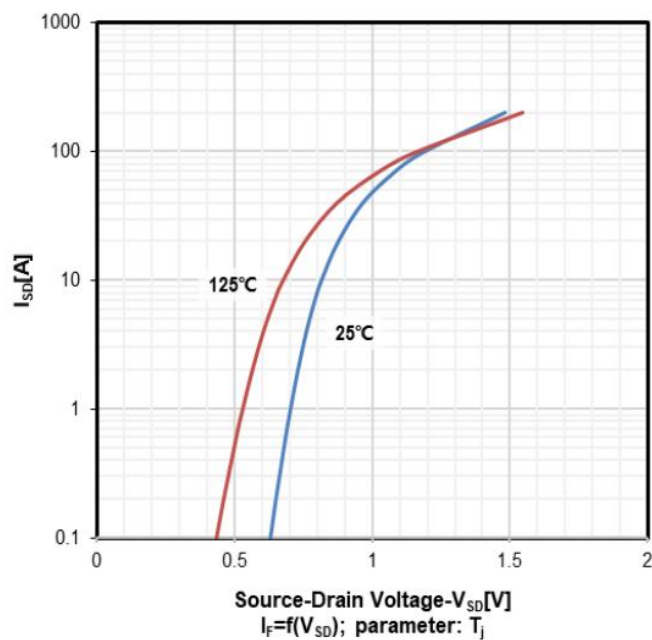
Typ. gate charge characteristics



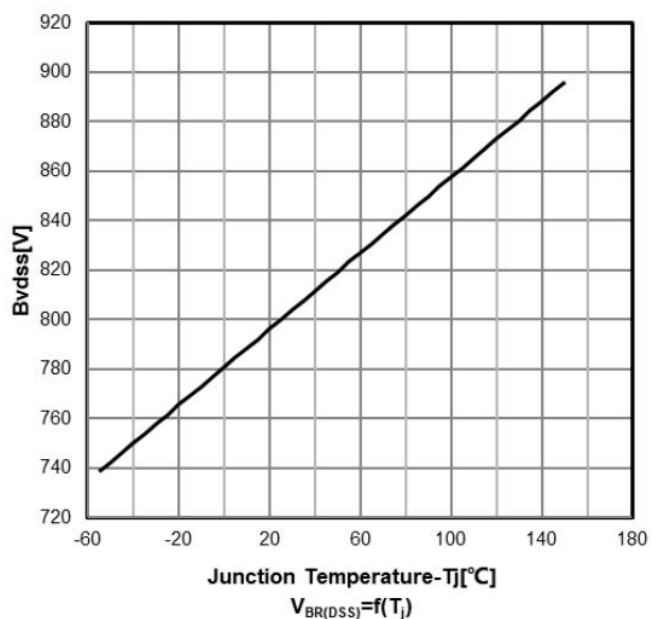
Power dissipation



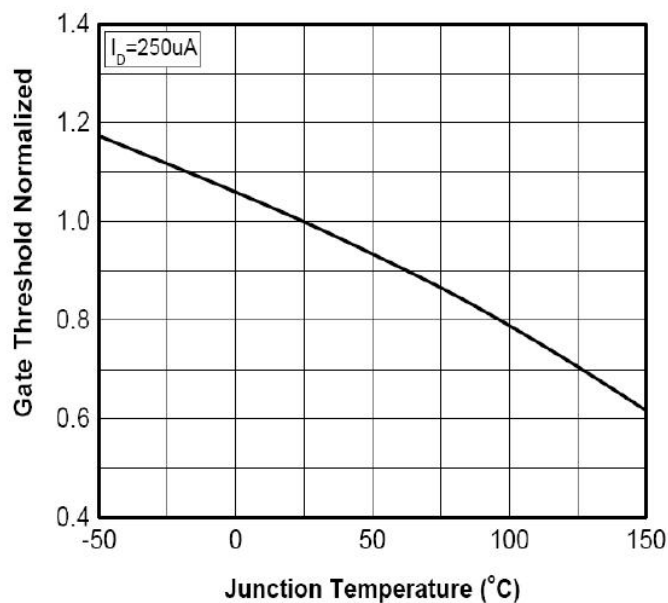
Forward characteristics of reverse diode



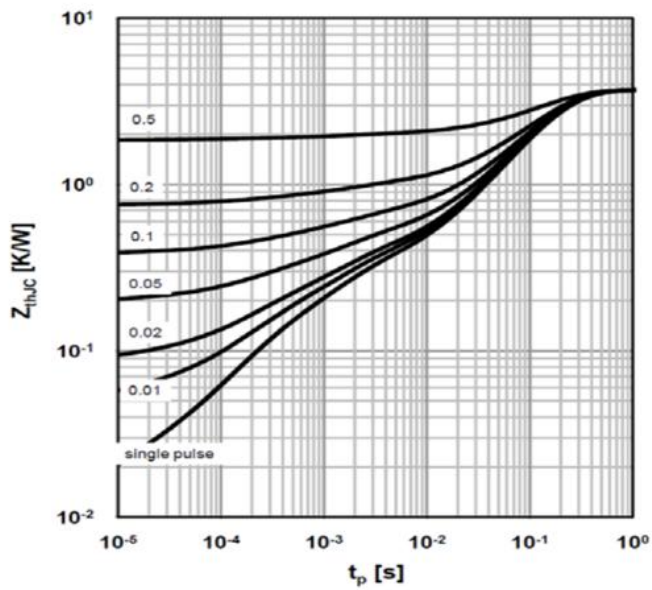
Drain-source breakdown voltage



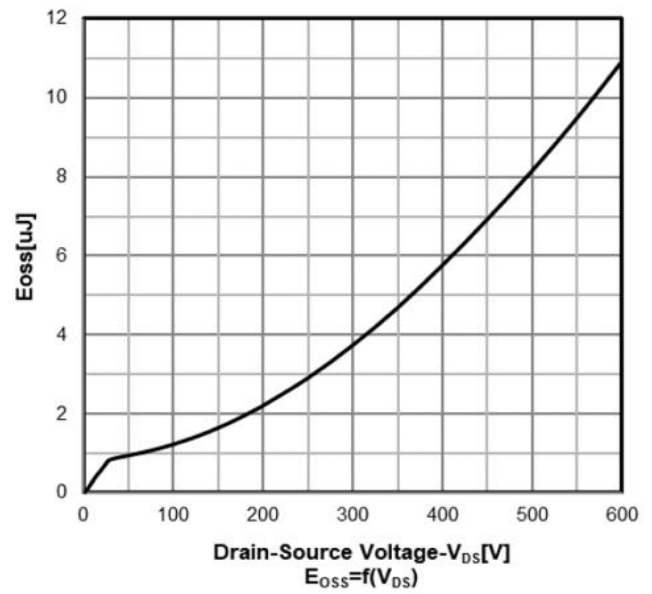
Normalized $V_{GS(th)}$ characteristics



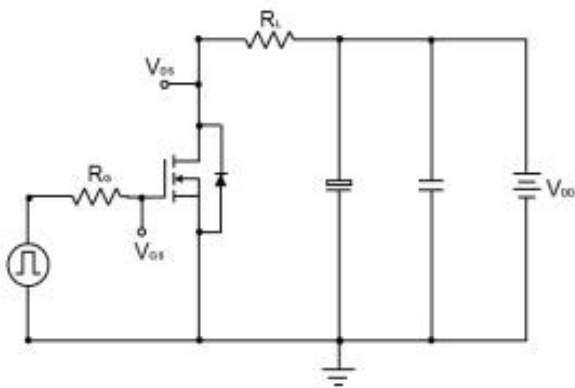
Max. transient thermal impedance
parameter: $D=t_p/T$; TO-220FullPAK



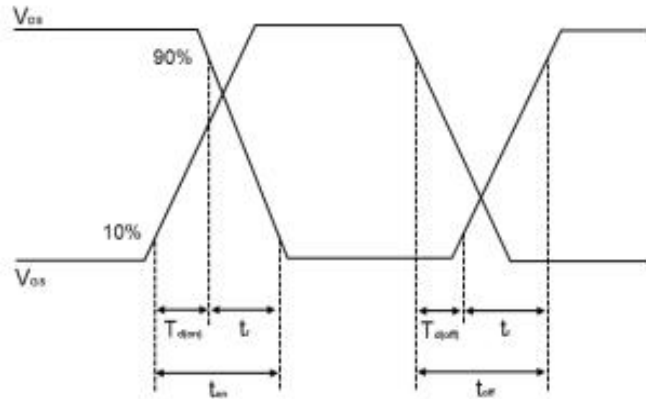
Coss stored energy



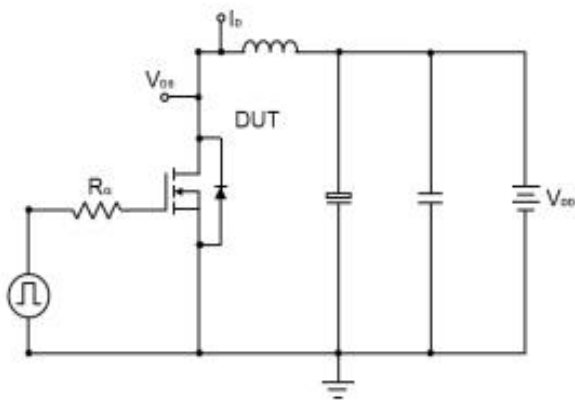
Test Circuits and Waveforms



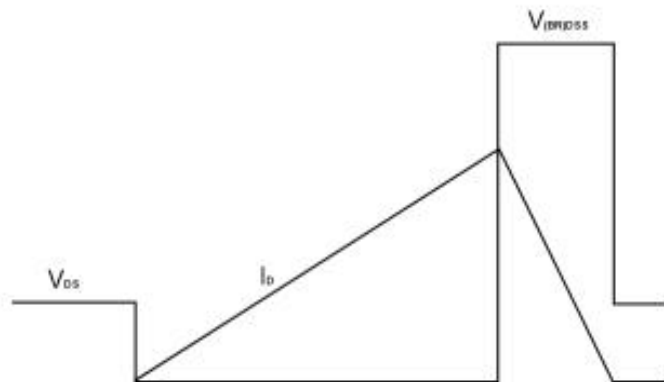
Test circuit for resistive load switching times



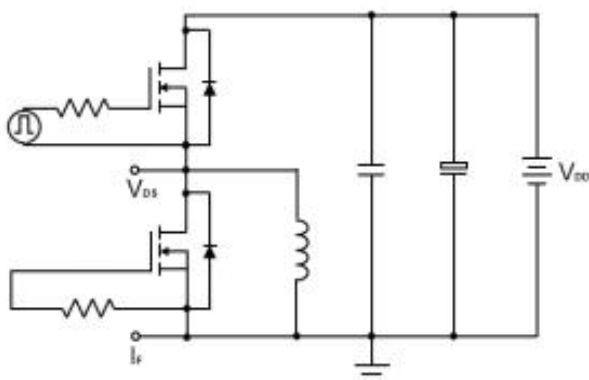
Switching times waveform



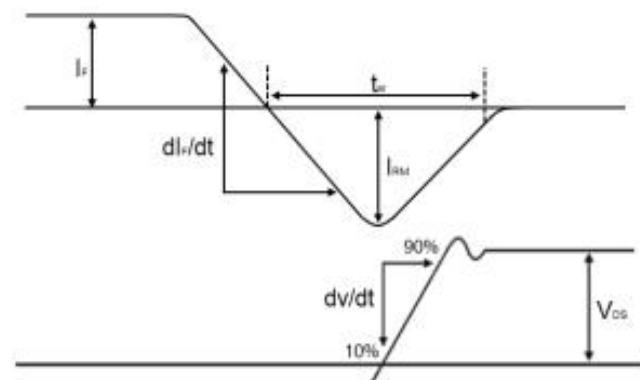
Test circuit for unclamped inductive load



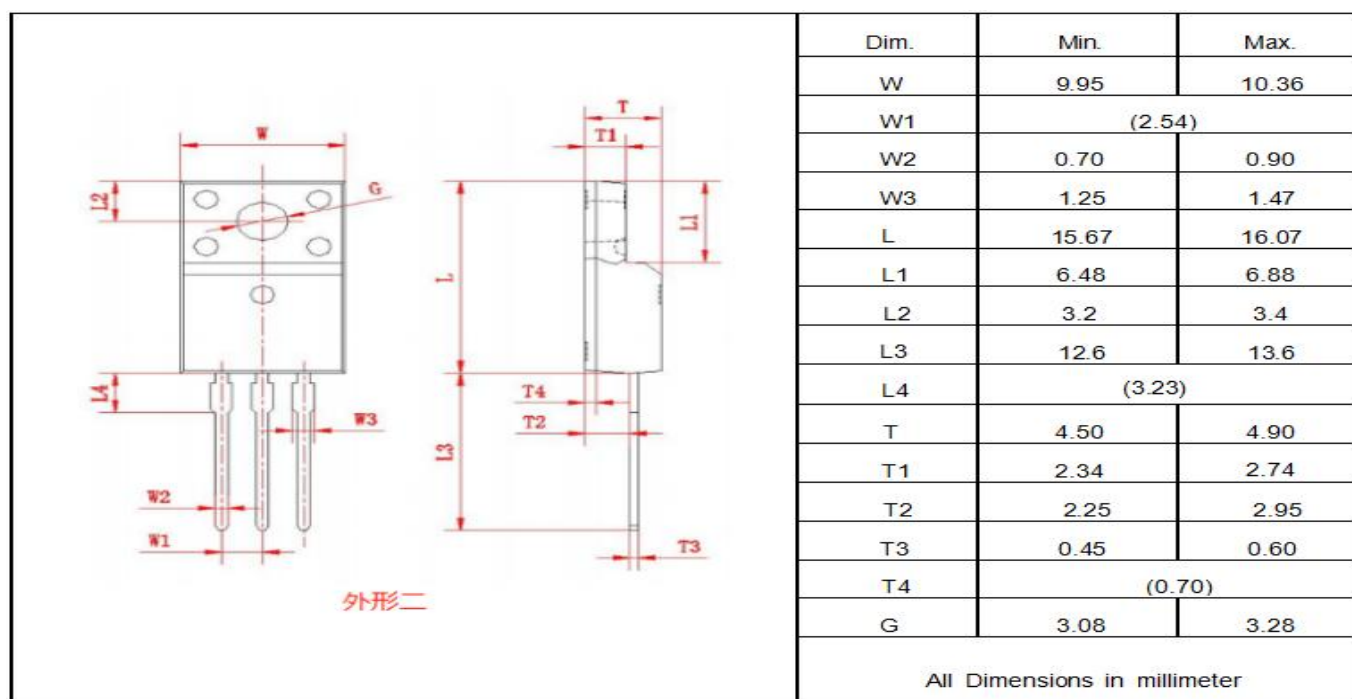
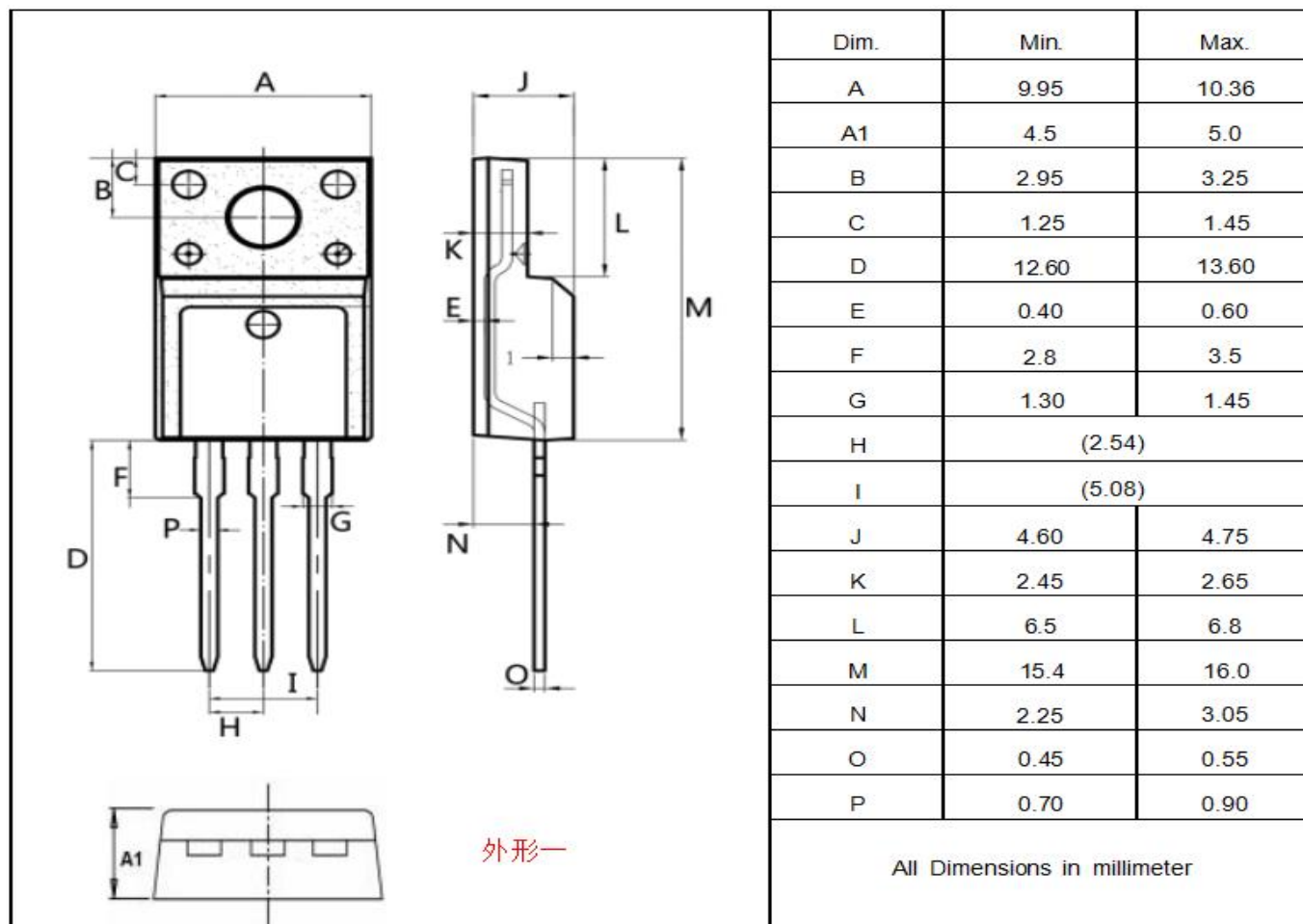
Unclamped inductive waveform



Test circuit for diode characteristics



Diode recovery waveform

Package outline drawing (TO-220F Unit: mm)


Disclaimers:

Reasunos Semiconductor Technology Co.Ltd (Reasunos) reserves the right to make changes without notice in order to improve reliability,function or design and to discontinue any product or service without notice .Customers should obtain the latest relevant information before orders and should verify that such information in current and complete.All products are sold subject to Reasunos's terms and conditions supplied at the time of orderacknowledgement.

Reasunos Semiconductor Technology Co.Ltd warrants performance of its hardware products to the specifications at the time of sale.Testing,reliability and quality control are used to the extene Reasunos deems necessary to support this warrantee. Except where agreed upon by contr- actual agreement,testing of all parameters of each product is not necessarily performed.

Reasunos Semiconductor Technology Co.Ltd does not assume any liability arising from the use of any product or circuit designs described herein.Customers are responsible for their products and applications using Reasunos's components.To minimize risk,customers must provide adequate design and operating safeguards.

Reasunos Semiconductor Technology Co.Ltd does not warrant or convey any license eith- er expressed or implied under its patent rights,nor the rights of others.Reproduction of inform- ation in Reasunos's data sheets or data books is permissible only if reproduction is without modification oralteration.Reproduction of this information with any alteration is an unfair and deceptive business practice. Reasunos Semiconductor Technology Co.Ltd is not responsi- ble or liable for such altered documentation.

Resale of Reasunos's products with statements different from or beyond the parameters stated by Reasunos Semiconductor Technology Co.Ltd for that product or service voids all exp- ress or implied warranties for the associated Reasunos's product or service and is unfair and deceptive business practice. Reasunos Semiconductor Technology Co.Ltd is not responsi- ble or liable for such statements.

Life Support Policy:

Reasunos Semiconductor Technology Co.Ltd's Products are not authorized for use as cri- tical components in life support devices or systems without the expressed written approval of Reasunos Semiconductor Technology Co.Ltd.

As used herein:

1. Life support devices or systems are devices or systems which: a.are intended for surgical implant into the human body, b.support or sustain life,c.whose failuer to when properly used in accordance with instructions for used provided in the laeling,can be reasonably expected to result in significant injury to the user.

2.A critical component is any component of a life support device or system whose failure to system whose failure to perform can be reasonably expected to cause the failure of the life support device or system,or to affect its safety or effectiveness.